Notice of References Cited

Application/Control No.

Applicant(s)/Patent Under Reexamination
BELCEA, JOHN M.

Examiner

Van Kim T. Nguyen

Applicant(s)/Patent Under Reexamination
BELCEA, JOHN M.

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α,	US-6,108,561	08-2000	Mallinckrodt, Albert Jack	455/522
	В	US-6,219,343	04-2001	Honkasalo et al.	370/335
	O	US-6,519,705	02-2003	Leung, Kin K.	713/300
	۵	US-6,243,591	06-2001	Takemura, Narihira	455/522
	Е	US-2002/0028691	03-2002	Moulsley et al.	455/522
	F	US-6,341,225	01-2002	Blanc, Patrick	455/522
	G	US-6,496,543	12-2002	Zehavi, Ephraim	375/295
	Ι	US-2002/0168993	11-2002	Choi et al.	455/522
	-	US-5,887,245	03-1999	Lindroth et al.	455/69
	J	US-5,634,195	05-1997	Sawyer, Francois	455/522
	К	US-5,806,003	09-1998	Jolma et al.	455/522
	L	US-6,366,572	04-2002	Esterberg et al.	370/343
	М	US-2002/0071395	06-2002	Redi et al.	370/252

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q				,	
	R					
	s					
	Т	-				

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	٧							
	w							
	×							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.